2SC4960

Silicon NPN triple diffusion planar type

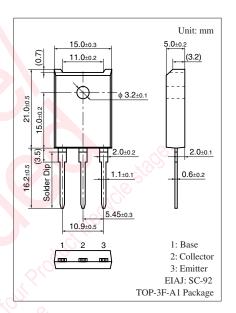
For power switching

■ Features

- High-speed switching
- ullet High collector-base voltage (Emitter open) V_{CBO}
- Satisfactory linearity of forward current transfer ratio h_{FE}
- Full-pack package with outstanding insulation, which can be installed to the heat sink with one screw

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V_{CBO}	900	V	
Collector-emitter voltage (E-B short)	V _{CES}	900	V	
Collector-emitter voltage (Base open)	V _{CEO}	800	V	
Emitter-base voltage (Collector open)	V_{EBO}	7	V	
Base current	I_{B}	0.3	A	
Collector current	I_{C}	1	A	
Peak collector current	I _{CP}	2	A	
Collector power dissipation	P_{C}	40	W	
$T_a = 25^{\circ}C$		3.0	S) 10	
Junction temperature	T_{j}	150	°C	
Storage temperature	$T_{\rm stg}$	-55 to +150	°C	

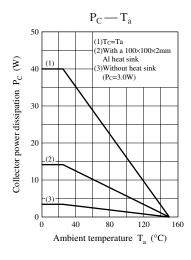


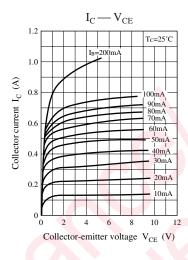
■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

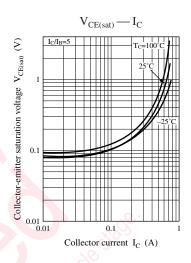
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = 1 \text{ mA}, I_B = 0$	800			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 900 \text{ V}, I_{E} = 0$			50	μΑ
Emitter-base cutoff current (Collector open)	I _{EBO}	$V_{EB} = 7 \text{ V}, I_{C} = 0$			50	μΑ
Forward current transfer ratio	h _{FE1}	$V_{CE} = 5 \text{ V}, I_{C} = 0.05 \text{ A}$	6			_
	h _{FE2}	$V_{CE} = 5 \text{ V}, I_{C} = 0.5 \text{ A}$	3			
Collector-emitter saturation voltage	V _{CE(sat)}	$I_C = 0.2 \text{ A}, I_B = 0.04 \text{ A}$			1.5	V
Base-emitter saturation voltage	V _{BE(sat)}	$I_C = 0.2 \text{ A}, I_B = 0.04 \text{ A}$			1.0	V
Transition frequency	f_T	$V_{CE} = 10 \text{ V}, I_{C} = 0.05 \text{ A}, f = 1 \text{ MHz}$		4		MHz
Turn-on time	t _{on}	$I_C = 0.2 \text{ A}$			1.0	μs
Storage time	t _{stg}	$I_{B1} = 0.04 \text{ A}, I_{B2} = -0.08 \text{ A}$			3.0	μs
Fall time	t _f	$V_{CC} = 250 \text{ V}$			1.0	μs

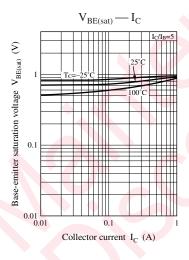
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

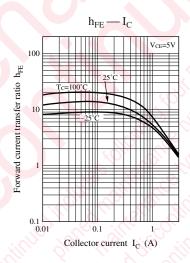
Publication date: February 2003 SJD00136BED 1

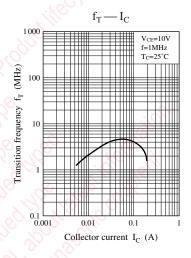


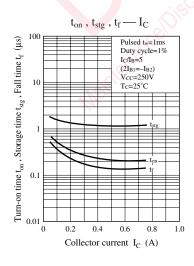


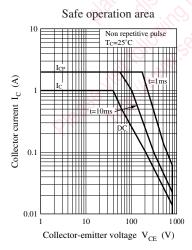






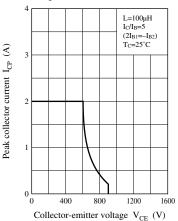




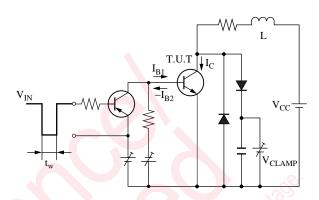


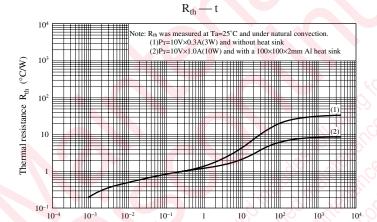
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Safe operation area (Reverse bias)



Safe operation area (Reverse bias) measuring circuit





Time t (s)

 10^{2}

 10^{-1}

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